FLEX™

UV-VIS-NIR Microspectrophotometer

Sophisticated UV-visible-NIR Microspectroscopy

FLEX™ from CRAIC Technologies is an integrated tool to measure the spectra of microscopic samples easily and cost effectively. Capable of absorbance, reflectance, polarization, fluorescence and photoluminescence, FLEX™ is also offered with 5D mapping, thin film thickness and Raman Microspectroscopy. In addition to all these spectral methods, the system is equipped for high resolution color imaging as well as automated operation.

The FLEX™ microspectrometer features the latest in Lightblades™ spectrometers, a technology designed specifically for high performance Microspectroscopy. Integrating advanced optics, software, hardware and the Lightblades™ spectrometers into a powerful yet flexible instrument, FLEX™ is built as a modular, durable but easy-to-use system. By combining all these features, the result is FLEX™: a powerful and rugged scientific instrument built for many years of productive work.

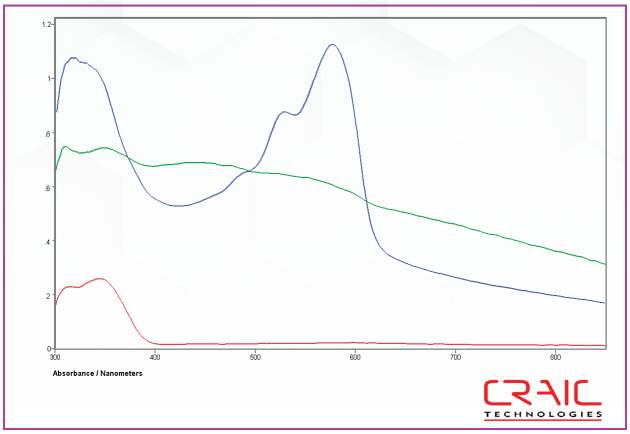
FLEX™ Key Features:

- Full UV-visible-NIR microspectroscopy in absorbance, transmission, reflectance, fluorescence and emission.
- Raman microspectroscopy with numerous laser wavelengths offered
- UV, visible and NIR imaging capabilities
- Calibrated variable sampling areas with Absolute Reproducibility
- Dual Reflectance and Transmittance Calibration Standards traceable to NIST

FLEX™ UV-vis-NIR Microspectrophotometer

FLEX™ SPECIFICATIONS

Types of Microspectroscopy	UV-vis-NIR absorbance, reflectance, fluorescence, photoluminescence, polarisation
Raman Microspectroscopy	Apollo II™
Thin Film Thickness	Film thickness ranges from 15 nm and up
Micro-kinetics	Available
5D Mapping	Available
Micro-colorimetry	Available
Microspectometer Spectral Range	240 - 900 nm
Microscope Imaging Range	High resolution color
Fluorescence Excitation	365 - 546 nm
Fluorescence Emission	400 - 900 nm
Spectrometer Model	Lightblades™
Detectors	Scientific grade CCD and InGaAs arrays
Detector Cooling	Thermoelectric
Spectral Resolution	User selectable, 1 - 15 nm
Sampling Area	Variable, 1 - 10,000 microns^2
Operating System	Windows



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Spectral Range

Calibration Standards

- ❑ Transmittance Standards traceable to NIST
- ❑ Reflectance Standards traceable to NIST
- ❑ White Diffuse Reflectance Standard traceable to NIST
- ❑ Vitrinite Coal Reflectance Standards
- ❑ Fluorescence Standards

System Software

- ❑ rIQ™ Glass Refractive Index
- ❑ Spectral 3D Mapping
- ❑ Thin Film Thickness Measurement
- ❑ TimePro Kinetics™
- ❑ Colorimetry
- ❑ Statistical Analysis

Accessories

- ❑ Quartz Slides and Coverslips
- ❑ CRAIC Certified Lamps
- ❑ Quartz Wellplates
- ❑ Specular Reflectance Material

Illumination Packages

- ❑ Transmission/Absorbance UV-VIS-NIR
- ❑ Reflectance UV-VIS-NIR
- ❑ Fluorescence UV-VIS-NIR
- ❑ Polarization

Spectrometer Packages

- ❑ High Resolution, 200-1000nm
- ❑ High Sensitivity, 200-900nm
- ❑ Standard Range NIR, 900-1700nm
- ❑ Extended Range NIR, 900-2100nm
- ❑ Standard UV-Visible-NIR 200-1700nm
- ❑ Extended UV-Visible-NIR 200-2100nm

Microspectroscopy Stages

- ❑ Manual XY
- ❑ Rotating & XY, 360deg/30mm x 40mm
- ❑ Semi-Rotating stage, up to 240deg
- ❑ Programmable XY Stage

CRAIC Technologies, Inc. 948 North Amelia Avenue, San Dimas, California 91773 USA Tel: +001-310-573-8180 | Fax: +001-310-573-8182
e-mail: sales@microspectra.com | web: www.microspectra.com
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